

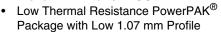


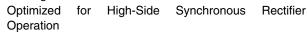
N-Channel 30-V (D-S) MOSFET

| PRODUCT SUMMARY | | | | | |
|---------------------|---|------------------------------------|-----------------------|--|--|
| V _{DS} (V) | $R_{DS(on)}(\Omega)$ | I _D (A) ^{a, g} | Q _g (Typ.) | | |
| 30 | 0.012 at V _{GS} = 10 V | 20 | 6.8 nC | | |
| | $0.015 \text{ at V}_{GS} = 4.5 \text{ V}$ | 20 | 0.0110 | | |

FEATURES

- Halogen-free
- TrenchFET[®] Power MOSFET





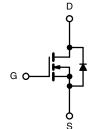


100 % UIS Tested

APPLICATIONS

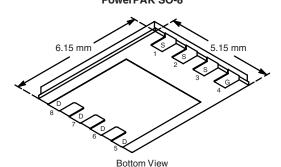
- Notebook CPU Core
 - High-Side Switch





N-Channel MOSFET

PowerPAK SO-8



Ordering Information: SiR472DP-T1-GE3 (Lead (Pb)-free and Halogen-free)

| ABSOLUTE MAXIMUM RATINGS | T _A = 25 °C, unles | s otherwise no | ted | | |
|--|-------------------------------|-----------------------------------|---------------------|------|--|
| Parameter | | Symbol | Limit | Unit | |
| Drain-Source Voltage | V_{DS} | 30 | - V | | |
| Gate-Source Voltage | V _{GS} | ± 20 | | | |
| | T _C = 25 °C | | 20 ^g | | |
| Continuous Drain Current (T _{.I} = 150 °C) | T _C = 70 °C | | 20 ^g | 1 | |
| Continuous Diain Current (1) = 150 C) | T _A = 25 °C | I _D | 14 ^{b, c} | | |
| | T _A = 70 °C | | 11 ^{b, c} |] A | |
| Pulsed Drain Current | | I _{DM} | 50 | 7 ^ | |
| Continuous Source-Drain Diode Current | T _C = 25 °C | I- | 20 ^g | 1 | |
| Continuous Source-Drain Diode Current | T _A = 25 °C | I _S | 3.2 ^{b, c} | 1 | |
| Single Pulse Avalanche Current | L = 0.1 mH | I _{AS} | 22 | | |
| Avalanche Energy | | E _{AS} | 24 | mJ | |
| | T _C = 25 °C | | 29.8 | | |
| Maximum Power Dissipation | T _C = 70 °C | $P_{\rm D}$ | 19.0 | w | |
| | T _A = 25 °C | L LD | 3.9 ^{b, c} | ¬ | |
| | T _A = 70 °C | | 2.5 ^{b, c} | | |
| Operating Junction and Storage Temperature Range | | T _J , T _{stg} | - 55 to 150 | | |
| Soldering Recommendations (Peak Temperature) ^{d, e} | | | 260 | °C | |

| THERMAL RESISTANCE RATINGS | | | | | | |
|---|--------------|------------|---------|---------|--------|--|
| Parameter | | Symbol | Typical | Maximum | Unit | |
| Maximum Junction-to-Ambient ^{b, f} | t ≤ 10 s | R_{thJA} | 27 | 32 | °C/W | |
| Maximum Junction-to-Case (Drain) | Steady State | R_{thJC} | 3.5 | 4.2 | - C/VV | |

Notes

- a. Base on T_C = 25 °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. See Solder Profile (http://www.vishay.com/ppg?73257). The PowerPAK SO-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under Steady State conditions is 70 °C/W.
- g. Package Limited.

Document Number: 68897 S-82488-Rev. C, 13-Oct-08

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| SPECIFICATIONS $T_J = 25 ^{\circ}\text{C}$ Parameter | Symbol | Test Conditions | Min. | Typ. | Max. | Unit | |
|--|-------------------------|--|---------|--------|--------|-------------|--|
| Static | Symbol | rest conditions | IVIIII. | тур. | IVIAA. | Oilit | |
| Drain-Source Breakdown Voltage | V _{DS} | V _{GS} = 0 V, I _D = 250 μA | 30 | | | V | |
| V _{DS} Temperature Coefficient | $\Delta V_{DS}/T_{J}$ | 30 5 | | 28 | | mV/°C | |
| V _{GS(th)} Temperature Coefficient | $\Delta V_{GS(th)}/T_J$ | I _D = 250 μA | | - 6 | | | |
| Gate-Source Threshold Voltage | V _{GS(th)} | V _{DS} = V _{GS} , I _D = 250 μA | 1.2 | | 2.5 | V | |
| Gate-Source Leakage | I _{GSS} | $V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$ | | | ± 100 | nA | |
| Zero Gate Voltage Drain Current | 400 | V _{DS} = 30 V, V _{GS} = 0 V | | 1 | | 1 | |
| | I _{DSS} | V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C | | | 10 | μΑ | |
| On-State Drain Current ^a | I _{D(on)} | $V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$ | 20 | | | Α | |
| | | V _{GS} = 10 V, I _D = 13.8 A | | 0.0097 | 0.0120 | Ω | |
| Drain-Source On-State Resistance ^a | R _{DS(on)} | V _{GS} = 4.5 V, I _D = 12.4 A | | 0.0122 | 0.0150 | | |
| Forward Transconductance ^a | 9 _{fs} | V _{DS} = 15 V, I _D = 13.8 A | | 52 | | S | |
| Dynamic ^b | | | | | l | l | |
| Input Capacitance | C _{iss} | | | 820 | | pF | |
| Output Capacitance | C _{oss} | V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz | | 195 | | | |
| Reverse Transfer Capacitance | C _{rss} | | | 73 | | | |
| Total Cata Chausa | | V _{DS} = 15 V, V _{GS} = 10 V, I _D = 13.8 A | | 15 | 23 | nC | |
| Total Gate Charge | Q_g | | | 6.8 | 10.2 | | |
| Gate-Source Charge | Q _{gs} | $V_{DS} = 15 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 13.8 \text{ A}$ | | 2.5 | | | |
| Gate-Drain Charge | Q _{gd} | | | 2.3 | | | |
| Gate Resistance | R_g | f = 1 MHz | 0.36 | 1.8 | 3.6 | Ω | |
| Turn-On Delay Time | t _{d(on)} | | | 16 | 24 | | |
| Rise Time | t _r | V_{DD} = 15 V, R_L = 1.4 Ω | | 12 | 18 | | |
| Turn-Off Delay Time | t _{d(off)} | $I_D \cong 11 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$ | | 16 | 24 | | |
| Fall Time | t _f | | | 10 | 20 | | |
| Turn-On Delay Time | t _{d(on)} | | | 8 | 16 | ns | |
| Rise Time | t _r | V_{DD} = 15 V, R_L = 1.4 Ω | | 10 | 20 | - - - | |
| Turn-Off Delay Time | t _{d(off)} | $I_D \cong 11 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$ | | 16 | 24 | | |
| Fall Time | t _f | | | 8 | 15 | | |
| Drain-Source Body Diode Characterist | tics | | | | | | |
| Continuous Source-Drain Diode Current | I _S | T _C = 25 °C | | | 25 | _ | |
| Pulse Diode Forward Current ^a | I _{SM} | | | | 50 | A | |
| Body Diode Voltage | V_{SD} | I _S = 2.6 A | | 0.8 | 1.2 | V | |
| Body Diode Reverse Recovery Time | t _{rr} | | | 15 | 30 | ns | |
| Body Diode Reverse Recovery Charge | Q _{rr} | L = 11 A dl/dt = 100 A/up T = 25 °C | | 6 | 12 | nC | |
| Reverse Recovery Fall Time | t _a | $I_F = 11 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$ | | 8 | | no | |
| Reverse Recovery Rise Time | t _b | | | 7 | | ns | |

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

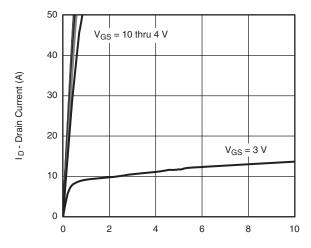
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





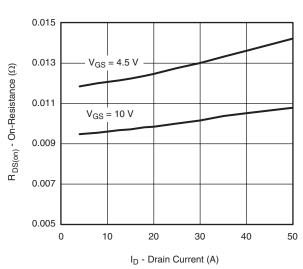


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

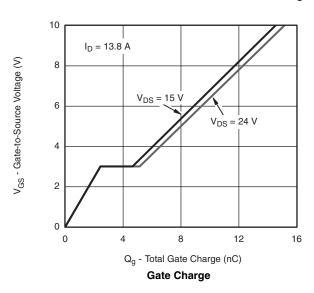


V_{DS} - Drain-to-Source Voltage (V)

Output Characteristics

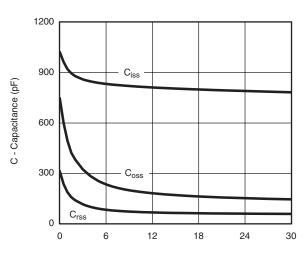


On-Resistance vs. Drain Current and Gate Voltage



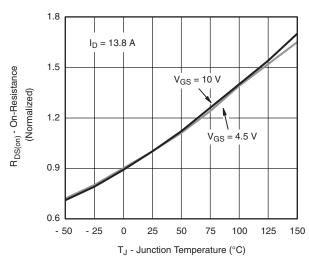
V_{GS} - Gate-to-Source Voltage (V)

Transfer Characteristics



V_{DS} - Drain-to-Source Voltage (V)

Capacitance

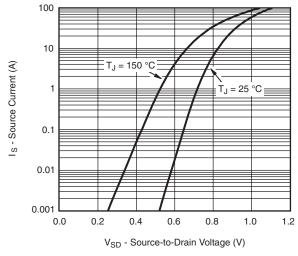


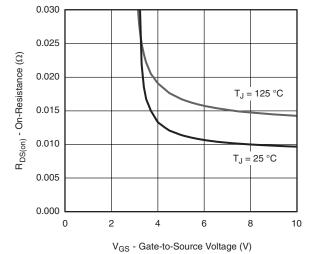
On-Resistance vs. Junction Temperature

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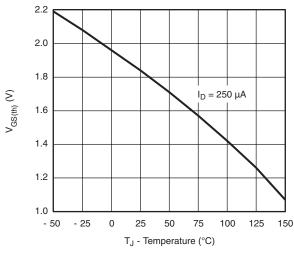
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

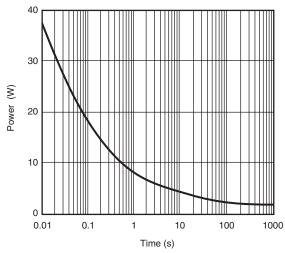




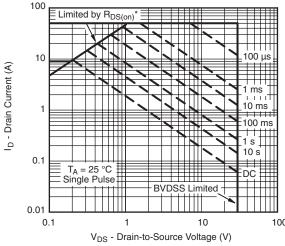
Source-Drain Diode Forward Voltage







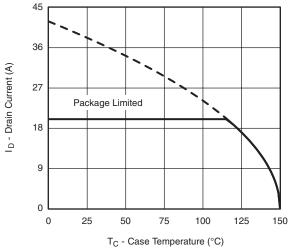
Threshold Voltage Single Pulse Power, Junction-to-Ambient



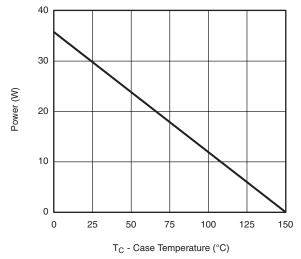
 * V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified Safe Operating Area, Junction-to-Ambient



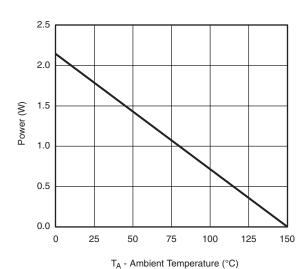
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted











Power Derating, Junction-to-Ambient

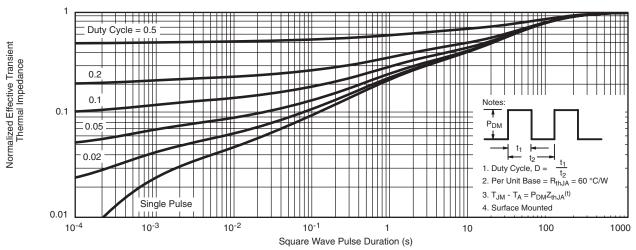
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^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit

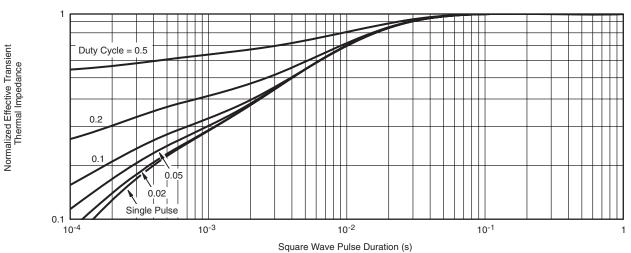
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

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Revision: 18-Jul-08

Document Number: 91000 www.vishay.com